

**Search Notes**

Application/Control No.

10/790,126

Examiner

HUYEN D. LE

Applicant(s)/Patent under  
Reexamination

BAYER, ERICH

Art Unit

2615

**SEARCHED**

Class	Subclass	Date	Examiner
38	322, 330, 324-328, 380-382	12/19/2006	HL
181	129		HL
181	130		HL
181	135		HL
600	25		HL
600	559		HL
607	56, 57		HL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Same as above		12/19/2006	HL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR